

Data Sheet Issue:- A1

Fast Recovery Diode Types M2325HA400 and M2325HA450

Absolute Maximum Ratings

| | VOLTAGE RATINGS | MAXIMUM LIMITS | UNITS |
|------|---|-------------------|-------|
| Vrrm | Repetitive peak reverse voltage, (note 1) | 4000-4500 | V |
| Vrsm | Non-repetitive peak reverse voltage, (note 1) | 4100-4600 | V |

| | OTHER RATINGS (note 6) | MAXIMUM LIMITS | UNITS |
|---------------------|--|----------------------|------------------|
| IF(AV) | Mean forward current, T _{sink} =55°C, (note 2) | 2325 | А |
| I _{F(AV)} | Mean forward current. T _{sink} =100°C, (note 2) | 1550 | А |
| F(AV) | Mean forward current. T _{sink} =100°C, (note 3) | 775 | А |
| I _{F(RMS)} | Nominal RMS forward current, T _{sink} =25°C, (note 2) | 4330 | А |
| F(d.c.) | D.C. forward current, T _{sink} =25°C, (note 4) | 3820 | А |
| IFSM | Peak non-repetitive surge t _p =10ms, V _{RM} =0.6V _{RRM} , (note 5) | 28.0 | kA |
| IFSM2 | Peak non-repetitive surge t _p =10ms, V _{RM} ≤10V, (note 5) | 30.8 | kA |
| l²t | $I^{2}t$ capacity for fusing t _p =10ms, V _{RM} =0.6V _{RRM} , (note 5) | 3.92×10 ⁶ | A ² s |
| l²t | $I^{2}t$ capacity for fusing t_p=10ms, V_{RM} \leq 10V, (note 5) | 4.74×10 ⁶ | A ² s |
| T _{HS} | Operating temperature range | -40 to +150 | °C |
| T _{stg} | Storage temperature range | -40 to +150 | °C |

Notes:-

1) De-rating factor of 0.13% per °C is applicable for T_j below 25°C.

2) Double side cooled, single phase; 50Hz, 180° half-sinewave.

3) Single side cooled, single phase; 50Hz, 180° half-sinewave.

4) Double side cooled.

5) Half-sinewave, 150°C T_j initial.



Characteristics

| | PARAMETER | MIN. | TYP. | MAX. | TEST CONDITIONS (Note 1) | UNITS | |
|-----------------------|--|------|------|--------|---|-------|--|
| Vfm | Maximum peak forward voltage | - | - | 2.60 | Іғм=2500А | V | |
| V ₀ | Threshold voltage | - | - | 1.581 | | V | |
| r _S | Slope resistance | - | - | 0.402 | | mΩ | |
| V | Novimum forward recovery voltage | - | - | 115 | di/dt = 1000A/µs | | |
| Vfrm | Maximum forward recovery voltage | - | - | 75 | di/dt = 1000A/µs, Tj=25°C | V | |
| I _{RRM} | Peak reverse current | - | - | 150 | Rated V _{RRM} | mA | |
| Qrr | Reverse Recovery Charge | - | 2400 | 2650 | | μC | |
| Q _{ra} | Recovered charge, 50% Chord | - | 1460 | - | I _{FM} =1000A, t _p =500μs, di/dt=200A/μs, | μC | |
| Irm | Reverse Recovery Current | - | 540 | - | Vr=50V, 50% Chord. | А | |
| t _{rr} | Reverse recovery time, 50% Chord | - | 5.4 | - | | μs | |
| | | - | - | 0.0105 | Double side cooled | | |
| R _{th(j-hs)} | Thermal resistance, junction to heatsink | - | - | 0.0173 | Anode side cooled | K/W | |
| | | - | - | 0.0273 | Cathode side cooled | | |
| F | Mounting force | 30 | - | 40 | | kN | |
| Wt | Weight | - | 1.2 | - | | kg | |

Notes:-

1) Unless otherwise indicated $T_j=150^{\circ}C$.



Notes on Ratings and Characteristics

1.0 Voltage Grade Table

| Voltage Grade | V _{RRM} (V) | V _{RSM} (V) | V _R dc (V) |
|---------------|-------------------------|-------------------------|--------------------------|
| 40 | 4000 | 4100 | 2000 |
| 45 | 4500 | 4600 | 2100 |

2.0 De-rating Factor

A blocking voltage de-rating factor of 0.13% per °C is applicable to this device for T_j below 25°C.

3.0 ABCD Constants

These constants (applicable only over current range of VF characteristic in Figure 1) are the coefficients of the expression for the forward characteristic given below:

$$V_F = A + B \cdot \ln(I_F) + C \cdot I_F + D \cdot \sqrt{I_F}$$

where I_F = instantaneous forward current.

4.0 Reverse recovery ratings

(i) Q_{ra} is based on 50% I_{rm} chord as shown in Fig.(a) below.



(ii) Qrr is based on a 150µs integration time.

$$Q_{rr} = \int_{0}^{150\,\mu s} i_{rr}.dt$$

1.6

K Factor =
$$\frac{t_1}{t_2}$$

(iii)



5.0 Reverse Recovery Loss

The following procedure is recommended for use where it is necessary to include reverse recovery loss.

From waveforms of recovery current obtained from a high frequency shunt (see Note 1) and reverse voltage present during recovery, an instantaneous reverse recovery loss waveform must be constructed. Let the area under this waveform be E joules per pulse. A new sink temperature can then be evaluated from:

$$T_{SINK} = T_{J(MAX)} - E \cdot \left[k + f \cdot R_{th(J-Hs)} \right]$$

Where k = 0.2314 (°C/W)/s

E = Area under reverse loss waveform per pulse in joules (W.s.)

f = Rated frequency in Hz at the original sink temperature.

 $R_{th(J-Hs)} = d.c.$ thermal resistance (°C/W)

The total dissipation is now given by:

$$W_{(tot)} = W_{(original)} + E \cdot f$$

NOTE 1 - Reverse Recovery Loss by Measurement

This device has a low reverse recovered charge and peak reverse recovery current. When measuring the charge, care must be taken to ensure that:

(a) AC coupled devices such as current transformers are not affected by prior passage of high amplitude forward current.

(b) A suitable, polarised, clipping circuit must be connected to the input of the measuring oscilloscope to avoid overloading the internal amplifiers by the relatively high amplitude forward current signal.

(c) Measurement of reverse recovery waveform should be carried out with an appropriate critically damped snubber, connected across diode anode to cathode. The formula used for the calculation of this snubber is shown below:

$$R^2 = 4 \cdot \frac{V_r}{C_s \cdot \frac{di}{dt}}$$

Where: V_r = Commutating source voltage C_S = Snubber capacitance

R = Snubber resistance



6.0 Computer Modelling Parameters

6.1 Device Dissipation Calculations

$$I_{AV} = \frac{-V_o + \sqrt{V_o^2 + 4 \cdot ff^2 \cdot r_s \cdot W_{AV}}}{2 \cdot ff^2 \cdot r_s}$$

Where $V_0 = 1.581$ V, $r_s = 0.402$ m Ω

ff = form factor (normally unity for fast diode applications)

$$W_{AV} = \frac{\Delta T}{R_{th}}$$
$$\Delta T = T_{j(MAX)} - T_{Hs}$$

6.2 Calculation of V_F using ABCD Coefficients

The forward characteristic I_F Vs V_F , on Fig. 1 is represented in two ways;

- (i) the well established V_0 and r_s tangent used for rating purposes and
- a set of constants A, B, C, and D forming the coefficients of the representative equation for V_F in terms of I_F given below:

$$V_F = A + B \cdot \ln(I_F) + C \cdot I_F + D \cdot \sqrt{I_F}$$

The constants, derived by curve fitting software, are given in this report for hot characteristics. The resulting values for V_F agree with the true device characteristic over a current range, which is limited to that plotted.

| | 25°C Coefficients | 150°C Coefficients |
|---|--------------------------|--------------------------|
| А | 0.613793358 | 0.130022348 |
| В | 0.08838485 | 0.1168203 |
| С | 1.86534×10 ⁻⁴ | 2.23322×10 ⁻⁴ |
| D | 0.01669329 | 0.01995332 |



Curves





Figure 2 - Maximum forward recovery voltage













Figure 5 - Maximum reverse current, Irm

Figure 6 - Maximum recovery time, trr (50% chord)















Figure 10 - Sine wave frequency vs. pulse width









Figure 14 - Square wave frequency vs pulse width



Figure 13 - Square wave frequency vs pulse width













Figure 17 – Maximum surge and I²t ratings



Figure 18 – Transient thermal impedance





Outline Drawing & Ordering Information







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